



EMI TEST REPORT

Test Report No. : 11413042H-B

Applicant : Sharp Corporation, Consumer Electronics Company,
Communication Systems Division

Type of Equipment : Smart Phone

Model No. : SH-02J

FCC ID : APYHRO00242

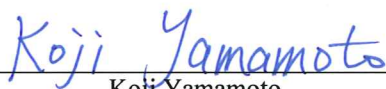
Test standard : FCC Part 15 Subpart B 2016 Class B

Test Result : Complied

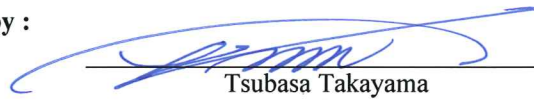
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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
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6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)

Date of test: August 22, 2016

**Representative
test engineer:**


Koji Yamamoto
Engineer
Consumer Technology Division

Approved by :


Tsubasa Takayama
Engineer
Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
http://japan.ul.com/resources/emc_accredited/

**UL Japan, Inc.
Ise EMC Lab.**

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13-EM-F0429

REVISION HISTORY

Original Test Report No.: 11413042H-B

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CONTENTS	PAGE
SECTION 1: Customer information	4
SECTION 2: Equipment under test (E.U.T.)	4
SECTION 3: Test specification, procedures & results	5
SECTION 4: Operation of E.U.T. during testing	8
SECTION 5: Conducted Emission	9
SECTION 6: Radiated Emission	10
APPENDIX 1: Test data	11
Conducted Emission	11
Radiated Emission	13
APPENDIX 2: Test instruments	17
APPENDIX 3: Photographs of test setup.....	18
Conducted Emission	18
Radiated Emission	19
Worst Case Position (Horizontal: Y-axis/ Vertical:Y-axis)	21

SECTION 1: Customer information

Company Name : Sharp Corporation, Consumer Electronics Company, Communication Systems Division
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima, 739-0192 Japan
Telephone Number : +81-82-420-1552
Facsimile Number : +81-82-420-1555
Contact Person : Hiroyuki Uwatoko

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Smart Phone
Model No. : SH-02J
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : August 17, 2016
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : SH-02J is Quad-band LTE(Band 1 / 3 / 5 / 19), Quad-band WCDMA(FDD I / V / VI / XIX) & Quad-band GSM(850 / 900 / 1800 / 1900) Multi-mode Smart Phone.
The EUT has the function that NFC, Bluetooth and Wireless-LAN technology interface for establishing contact and transmitting data with certain device.
Clock frequencies in the system : CPU: 1.401GHz (max)
Source oscillation: 19.2MHz, 27.12MHz(NFC), 48MHz(BT/WLAN)
The maximum frequency for radio use : 2480 MHz (Bluetooth 79ch)

SECTION 3: Test specification, procedures & results

3.1 Test specification

Test specification : FCC Part 15 Subpart B
FCC part 15 final revised on April 6, 2016.

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2014 7. AC power - line conducted emission measurements	Class B	N/A	[QP] 13.4 dB 0.66537 MHz, N [AV] 4.6 dB 0.66379 MHz, L	Complied
Radiated emission	ANSI C63.4: 2014 8. Radiated emission measurements	Class B	N/A	8.5 dB 72.031 MHz, Horizontal, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.

Frequency range	Conducted emission using AMN(LISN) (+/-)
0.009 – 0.15MHz	3.5 dB
0.15 – 30MHz	3.0 dB

Polarity	Radiated emission (Below 1GHz)			
	(3 m*)(+/-)		(10 m*)(+/-)	
	30 – 200 MHz	200 – 1000MHz	30 – 200 MHz	200 – 1000MHz
Horizontal	5.0 dB	5.3 dB	5.0 dB	5.0 dB
Vertical	4.7 dB	5.9 dB	5.0 dB	5.1 dB

Radiated emission (Above 1GHz)				
(3 m*)(+/-)		(1 m*)(+/-)		(10 m*)(+/-)
1 – 6GHz	6 – 18GHz	10 – 26.5 GHz	26.5 – 40GHz	1 -18 GHz
5.2 dB	5.4 dB	5.5 dB	5.5 dB	5.4 dB

* Measurement distance

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3 m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

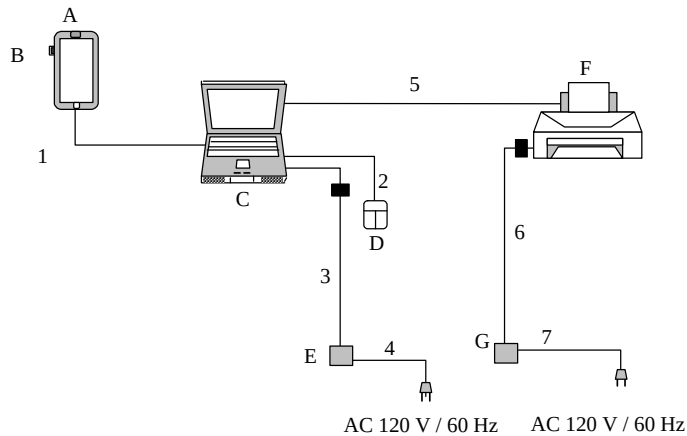
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



■ : Ferrite core which has been standard on support equipment.

*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Smart Phone	SH-02J	004401/11/584138/5	Sharp Corporation	EUT
B	microSD Memory Card	SD-C02G	None	TOSHIBA	-
C	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	Dell	-
D	Mouse	M-UAG120	LZ733B70EVV	TOSHIBA	-
E	AC Adapter(PC)	PA-1900-02D	CN-09T215-71615-52C-1062	Dell	-
F	Printer	895Cxi	SG8BA1W18J	Hewlett Packard	-
G	AC Adapter(Printer)	C4557-60004	C8L01B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	0.95	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adapter Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	0.85	Unshielded	Unshielded	-
5	Parallel Cable	1.85	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place	: No. 1 semi anechoic chamber
Temperature	: See data
Humidity	: See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30 cm to 40 cm long and were hanged at a 40 cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 3.

Frequency range	: 0.15 MHz - 30 MHz
EUT position	: Table top
EUT operation mode	: See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type	: Quasi-Peak and CISPR AV
IF Bandwidth	: 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: August 22, 2016

Test engineer: Koji Yamamoto

SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the center the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30 MHz - 200 MHz (Biconical antenna) / 200 MHz - 1000 MHz (Logperiodic antenna)
1000 MHz – 13 GHz (Horn antenna)
Test distance : 3 m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.

The radiated emission measurements were made with the following detector function of the Test Receiver.

Frequency	Below 1 GHz	Above 1 GHz *1)
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120 kHz	PK: BW 1 MHz, CISPR AV: BW 1 MHz

*1) The measurement data was adjusted to a 3 m distance using the following Distance Factor.

Distance Factor: $20 \times \log(3.5\text{m} / 3\text{m}) = 1.34\text{dB}$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: August 22, 2016

Test engineer: Koji Yamamoto

APPENDIX 1: Test data

Conducted Emission

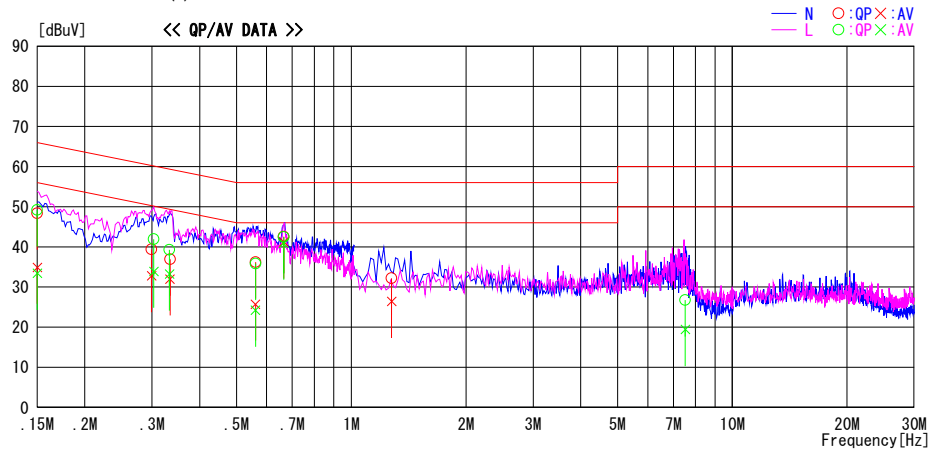
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/08/22

Report No. : 11413042H
Temp./Humi. : 23deg. C / 57% RH
Engineer : Koji Yamamoto

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	35.2	21.7	13.2	48.4	34.9	66.0	56.0	17.6	21.1	N	
0.29940	26.1	19.5	13.3	39.4	32.8	60.3	50.3	20.9	17.5	N	
0.33471	23.6	18.7	13.3	36.9	32.0	59.3	49.3	22.4	17.3	N	
0.56101	22.9	12.4	13.3	36.2	25.7	56.0	46.0	19.8	20.3	N	
0.66537	29.3	27.9	13.3	42.6	41.2	56.0	46.0	13.4	4.8	N	
1.27566	18.8	13.0	13.4	32.2	26.4	56.0	46.0	23.8	19.6	N	
0.15000	36.0	20.2	13.2	49.2	33.4	66.0	56.0	16.8	22.6	L	
0.30343	28.6	20.6	13.3	41.9	33.9	60.1	50.1	18.2	16.2	L	
0.33355	26.0	19.9	13.3	39.3	33.2	59.4	49.4	20.1	16.2	L	
0.56110	22.5	10.9	13.3	35.8	24.2	56.0	46.0	20.2	21.8	L	
0.66479	29.2	27.6	13.3	42.5	40.9	56.0	46.0	13.5	5.1	L	
7.52352	12.5	5.2	14.2	26.7	19.4	60.0	50.0	33.3	30.6	L	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTEN + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

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Radiated Emission
(Below 1GHz)

DATA OF RADIATED EMISSION TEST

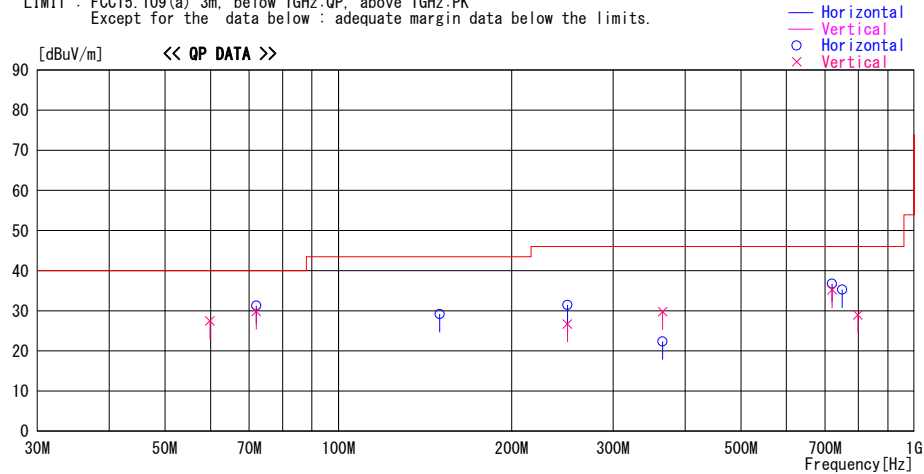
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/08/22

Order No. : 11413042H

Temp./Humi. : 22deg. C / 55% RH
Engineer : Koji Yamamoto

Mode / Remarks : USB Data Com Mode Axis-Y

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]	
59.824	51.2	QP	7.5	-31.2	27.5	96	100	Vert.	40.0	12.5	
72.032	56.3	QP	6.2	-31.2	31.3	95	251	Hori.	40.0	8.7	
72.032	54.9	QP	6.2	-31.2	29.9	106	100	Vert.	40.0	10.1	
149.920	44.5	QP	14.8	-30.1	29.2	271	300	Hori.	43.5	14.3	
250.000	47.8	QP	12.5	-28.8	31.5	277	100	Hori.	46.0	14.5	
250.000	43.0	QP	12.5	-28.8	26.7	169	200	Vert.	46.0	19.3	
365.758	35.1	QP	14.9	-27.6	22.4	101	100	Hori.	46.0	23.6	
365.758	42.5	QP	14.9	-27.6	29.8	195	100	Vert.	46.0	16.2	
719.983	41.8	QP	20.0	-25.1	36.7	138	100	Hori.	46.0	9.3	
719.983	40.3	QP	20.0	-25.1	35.2	74	100	Vert.	46.0	10.8	
749.980	39.9	QP	20.3	-24.9	35.3	55	100	Hori.	46.0	10.7	
798.127	32.8	QP	20.8	-24.6	29.0	70	200	Vert.	46.0	17.0	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-200MHz:BICONICAL, 200MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

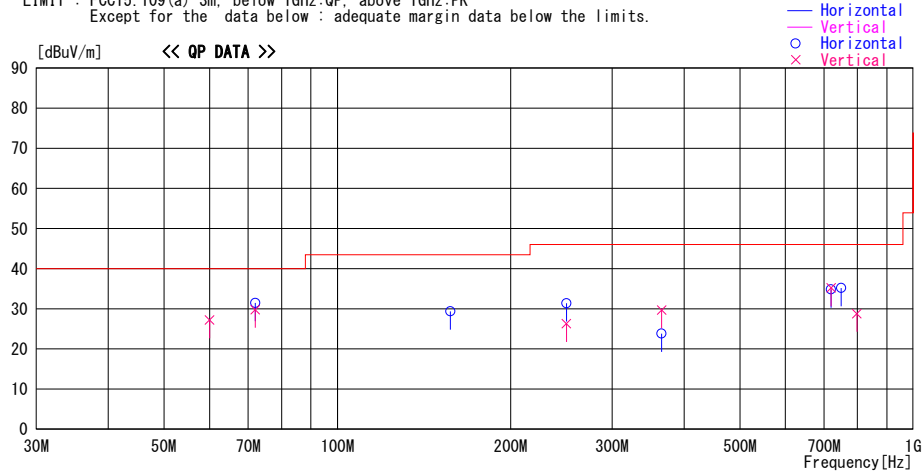
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Date : 2016/08/22

Order No. : 11413042H

Temp./Humi. : 22deg. C / 55% RH
Engineer : Koji Yamamoto

Mode / Remarks : Standby Mode Axis-Y

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]	
59.980	51.0	QP	7.4	-31.2	27.2	91	100	Vert.	40.0	12.8	
72.031	56.5	QP	6.2	-31.2	31.5	117	300	Hori.	40.0	8.5	
72.031	54.8	QP	6.2	-31.2	29.8	95	100	Vert.	40.0	10.2	
157.075	44.3	QP	15.1	-30.0	29.4	258	300	Hori.	43.5	14.1	
250.000	47.7	QP	12.5	-28.8	31.4	301	100	Hori.	46.0	14.6	
250.000	42.6	QP	12.5	-28.8	26.3	165	200	Vert.	46.0	19.7	
365.658	36.5	QP	14.9	-27.6	23.8	283	100	Hori.	46.0	22.2	
365.658	42.4	QP	14.9	-27.6	29.7	217	100	Vert.	46.0	16.3	
719.983	39.9	QP	20.0	-25.1	34.8	116	100	Hori.	46.0	11.2	
719.983	40.3	QP	20.0	-25.1	35.2	70	100	Vert.	46.0	10.8	
749.998	39.8	QP	20.3	-24.9	35.2	124	100	Hori.	46.0	10.8	
798.099	32.6	QP	20.8	-24.6	28.8	75	200	Vert.	46.0	17.2	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-200MHz:BICONICAL, 200MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTN - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

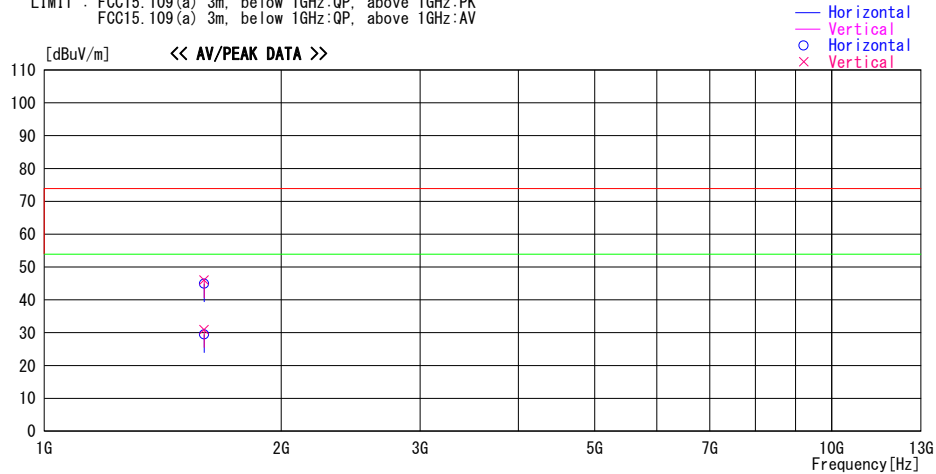
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Date : 2016/08/22

Order No. : 11413042H

Temp./Humi. : 22deg. C / 55% RH
Engineer : Koji Yamamoto

Mode / Remarks : USB Data Com Mode Axis-Y

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]	
1596.320	52.4	PK	25.3	-32.8	44.9	276	117	Hori.	73.9	29.0	
1596.320	53.6	PK	25.3	-32.8	46.1	354	117	Vert.	73.9	27.8	
1596.320	37.0	AV	25.3	-32.8	29.5	276	117	Hori.	53.9	24.4	
1596.320	38.5	AV	25.3	-32.8	31.0	354	117	Vert.	53.9	22.9	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-200MHz:BICONICAL, 200MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP) + D.FACTOR)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

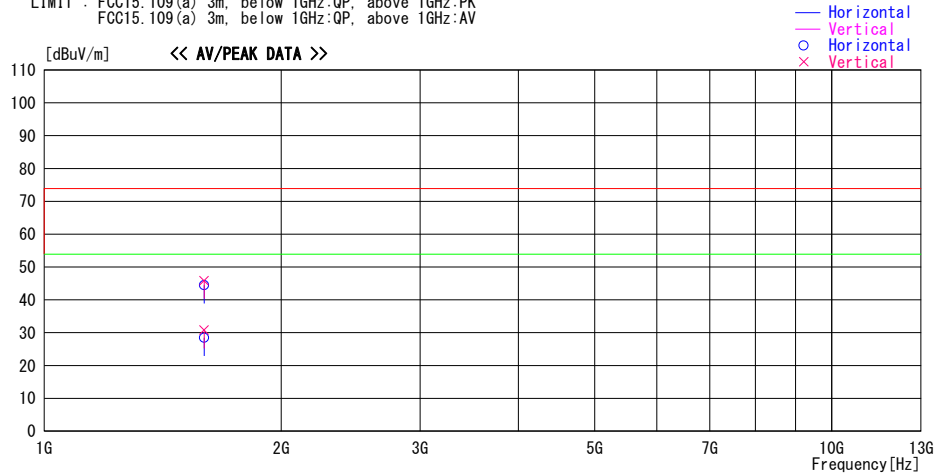
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2016/08/22

Order No. : 11413042H

Temp./Humi. : 22deg. C / 55% RH
Engineer : Koji Yamamoto

Mode / Remarks : Standby Mode Axis-Y

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]	
1596.320	52.0	PK	25.3	-32.8	44.5	280	115	Hori.	73.9	29.4	
1596.320	53.4	PK	25.3	-32.8	45.9	5	117	Vert.	73.9	28.0	
1596.320	36.0	AV	25.3	-32.8	28.5	280	115	Hori.	53.9	25.4	
1596.320	38.3	AV	25.3	-32.8	30.8	5	117	Vert.	53.9	23.1	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-200MHz:BICONICAL, 200MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP) + D.FACTOR)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2015/09/19 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2016/01/21 * 12
MJM-25	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2016/06/25 * 12
MLS-25	LISN(AMN)	Schwarzbeck	NSLK8127	8127-731	CE(EUT)	2016/07/21 * 12
MLS-26	LISN(AMN)	Schwarzbeck	NSLK8127	8127-732	CE(AE)	2016/07/25 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2016/01/15 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/3D-2W(7.5m)/RG400u(1.5m)/RFM-E421(Switcher)	- /01068(Switcher)	CE	2016/06/29 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2016/01/14 * 12
MMM-03	Digital Tester	Fluke	FLUKE 26-3	78030621	RE/CE	2015/08/19 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2015/11/02 * 12
MLA-20	Logperiodic Antenna(200-1000MHz)	Schwarzbeck	VUSLP9111B	911B-189	RE	2016/01/30 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2015/11/10 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2015/09/29 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2016/02/25 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2016/05/29 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2016/02/26 * 12
MCC-167	Microwave Cable	Junkosha	MWX221	1404S374(1m) / 1405S074(5m)	RE	2016/05/20 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emission

RE: Radiated Emission

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